

RF amplifier and high speed switch

The BFR 11 is an NPN silicon planar epitaxial transistor designed for RF amplifiers and high speed switching applications.

This device features a minimum f_T of 250 MHz at 50 mA, $V_{CE} = 10$ V together with a maximum $V_{CE}(\text{sat})$ of 0.6 V at 500 mA.

ELECTRICAL CHARACTERISTICS

($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Characteristic and test conditions	Min.	Typ.	Max.	Unit
h_{FE}	DC Current Gain				
	$I_C = 100 \mu\text{A}$ $V_{CE} = 10$ V	25	50		
	$I_C = 10$ mA $V_{CE} = 10$ V (5)	50	85		
	$I_C = 150$ mA $V_{CE} = 10$ V (6)	60	90	120	
	$I_C = 500$ mA $V_{CE} = 10$ V (5)	40	65		
$V_{BE(\text{sat})}$	Base Saturation Voltage				
	$I_C = 150$ mA $I_B = 15$ mA	0.7	0.45	1	V
	$I_C = 500$ mA $I_B = 50$ mA		1.05	1.3	V
$V_{CE(\text{sat})}$	Collector Saturation Voltage (5)				
	$I_C = 150$ mA $I_B = 15$ mA		0.14	0.22	V
	$I_C = 500$ mA $I_B = 50$ mA		0.40	0.60	V
I_{CES}	Collector Reverse Current				
	$V_{CE} = 60$ V $V_{EB} = 0$		0.2	10	nA
	$V_{CE} = 60$ V $V_{EB} = 0$ (150°C)		0.2	10	μA
I_{EBO}	Emitter Reverse Current				
$V_{EB} = 3$ V $I_C = 0$				10	nA
BV_{CES}	Collector to Emitter Breakdown Voltage				
$I_C = 10$ mA $V_{EB} = 0$		75			V
BV_{EBO}	Emitter to Base Breakdown Voltage				
$I_E = 10 \mu\text{A}$ $I_C = 0$		6			V
V_{CER}	Collector to Emitter Sustaining Voltage (4 and 5)				
	$I_C = 30$ mA $I_B = 0$	40			V
h_{fe}	Small Signal Current Gain ($f = 1\text{kHz}$)				
$I_C = 10$ mA $V_{CE} = 10$ V			90		
h_{ie}	Input Resistance ($f = 1\text{kHz}$)				
$I_C = 10$ mA $V_{CE} = 10$ V			350		Ω
h_{oe}	Output Conductance ($f = 1\text{kHz}$)				
$I_C = 10$ mA $V_{CE} = 10$ V			30		mho
h_{fe}	Voltage Feedback Ratio ($f = 1\text{kHz}$)				
$I_C = 10$ mA $V_{CE} = 10$ V			12		$\times 10^{-4}$
h_{fe}	High Freq. Current Gain ($f = 100\text{MHz}$)				
$I_C = 50$ mA $V_{CE} = 10$ V		2.5	3.5		
C_{TE}	Emitter Transition Capacitance				
$I_C = 0$ $V_{EB} = 0.5$ V			14	25	pF
C_{ob}	Base-Collector Capacitance				
	$I_E = 0$ $V_{CB} = 10$ V		5	8	pF
t_{on}	Turn On Time				
$I_C = 300$ mA $I_B1 = 30$ mA			14	60	ns
t_{off}	Turn Off Time				
	$I_C = 300$ mA $I_B1 = 30$ mA $I_B2 = 20$ mA		60	150	ns

ABSOLUTE MAXIMUM RATINGS (1)

($T_A = 25^\circ\text{C}$ unless otherwise noted)

Voltages

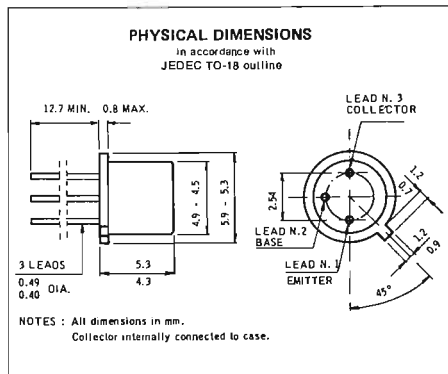
Collector to Emitter (4)	V_{CEO}	40 V
Collector to Emitter	V_{CES}	75 V
Emitter to Base	V_{EBO}	6 V

Temperatures

Storage Temperature Range	T_{STG}	-55°C to 200°C
Junction Temperature	T_J	200°C
Lead Temperature (Soldering, 10 sec.)	T_L	260°C

Power (2 and 3)

Dissipation at 25°C Case Temperature	P_D	1.5 W
Dissipation at 25°C Ambient Temperature	P_D	0.4 W



NOTES:

- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- These ratings give a maximum junction temperature of 200°C and junction-to-case thermal resistance of 117°C/W (derating factor of $8.6 \text{ mW}/^\circ\text{C}$); junction-to-ambient thermal resistance of 4.3°C/W (derating factor of $2.28 \text{ mW}/^\circ\text{C}$).
- These ratings refer to a high-current point where collector-to-emitter voltage is lowest. For more information send for SGS AR 5.
- Measured under pulse conditions: pulse length = 300 μsec ; duty cycle 1%.